

Power MOSFET

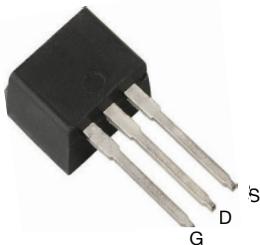
PRODUCT SUMMARY	
V _{DS} (V)	950
R _{DSON} (Ω)	V _{GS} = 10 V 5.4
Q _g (Max.) (nC)	78
Q _{gs} (nC)	10
Q _{gd} (nC)	42
Configuration	Single

FEATURES

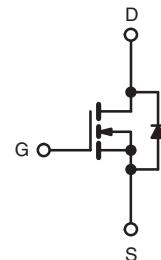
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



TO-262



Top View



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	950	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current	I _D	3.6	A
		2.3	
Pulsed Drain Current ^a	I _{DM}	14	
Linear Derating Factor		1.0	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	250	mJ
Repetitive Avalanche Current ^a	I _{AR}	3.6	A
Repetitive Avalanche Energy ^a	E _{AR}	13	mJ
Maximum Power Dissipation	P _D	125	W
Peak Diode Recovery dV/dt ^c	dV/dt	1.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

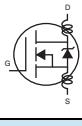
Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
 b. V_{DD} = 50 V, starting T_J = 25 °C, L = 36 mH, R_g = 25 Ω, I_{AS} = 3.6 A (see fig. 12).
 c. I_{SD} ≤ 3.6 A, dI/dt ≤ 70 A/μs, V_{DD} ≤ 600, T_J ≤ 150 °C.
 d. 1.6 mm from case.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

SPECIFICATIONS ($T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		950	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	1.1	-	$\text{V}/^{\circ}\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 900 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	100	μA	
		$V_{DS} = 720 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ }^{\circ}\text{C}$		-	-	500		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 2.2 \text{ A}^b$	--	5.4	-	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 100 \text{ V}, I_D = 2.2 \text{ A}^b$		2.3	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1.0 \text{ MHz}$, see fig. 5		-	1200	-	pF	
Output Capacitance	C_{oss}			-	320	-		
Reverse Transfer Capacitance	C_{rss}			-	200	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 3.6 \text{ A}, V_{DS} = 360 \text{ V}, \text{see fig. 6 and 13}^b$	-	-	78	nC	
Gate-Source Charge	Q_{gs}			-	-	10		
Gate-Drain Charge	Q_{gd}			-	-	42		
Turn-On Delay Time	$t_{d(on)}$			-	14	-		
Rise Time	t_r	$V_{DD} = 450 \text{ V}, I_D = 3.6 \text{ A}, R_g = 12 \Omega, R_D = 120 \Omega$, see fig. 10 ^b		-	25	-	ns	
Turn-Off Delay Time	$t_{d(off)}$			-	90	-		
Fall Time	t_f			-	30	-		
Internal Drain Inductance	L_D			-	4.5	-		
Internal Source Inductance	L_S	Between lead, 6 mm (0.25") from package and center of die contact 		-	7.5	-	nH	
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.6	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	14		
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}, I_S = 3.6 \text{ A}, V_{GS} = 0 \text{ V}^b$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}, I_F = 3.6 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	430	650	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.4	2.1	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

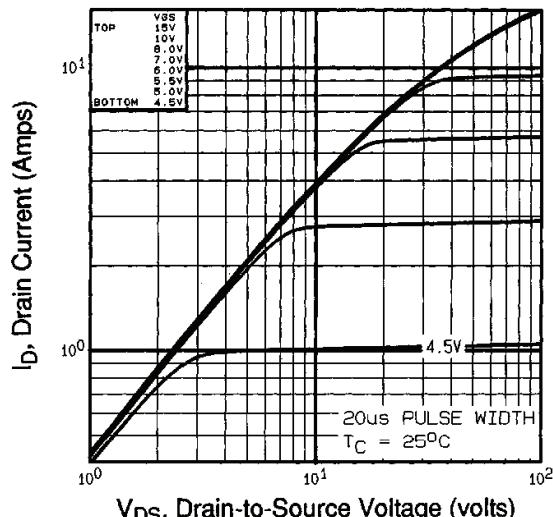
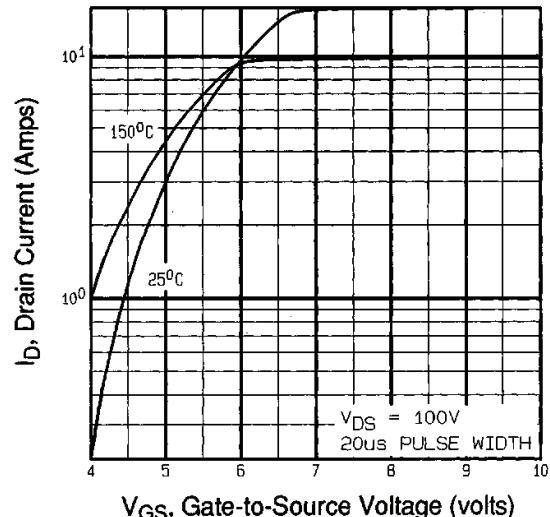
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$ 

Fig. 3 - Typical Transfer Characteristics

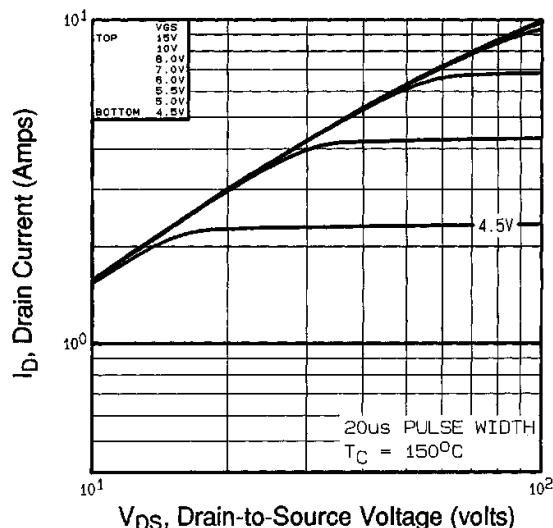
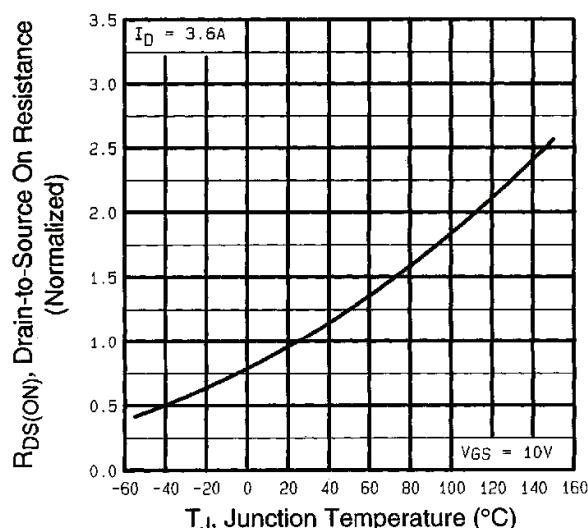
Fig. 2 - Typical Output Characteristics, $T_C = 150\text{ }^\circ\text{C}$ 

Fig. 4 - Normalized On-Resistance vs. Temperature

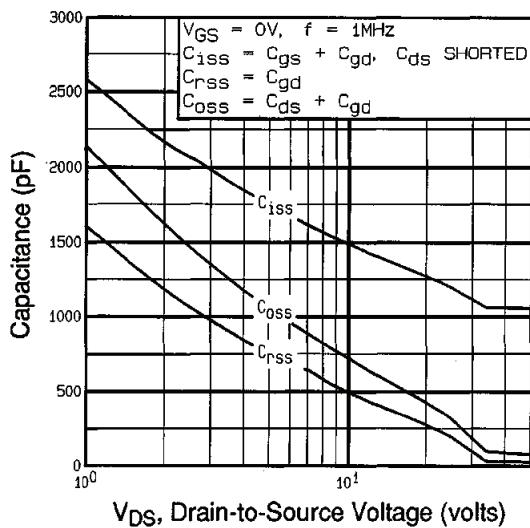


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

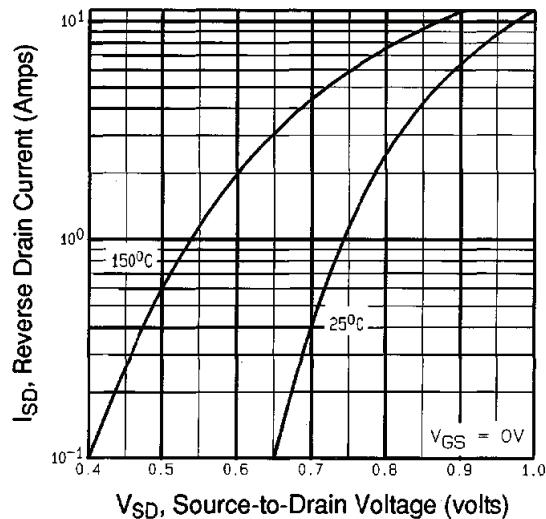


Fig. 7 - Typical Source-Drain Diode Forward Voltage

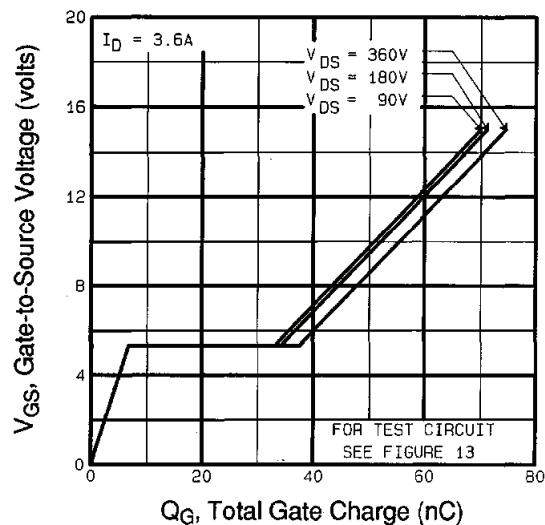


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

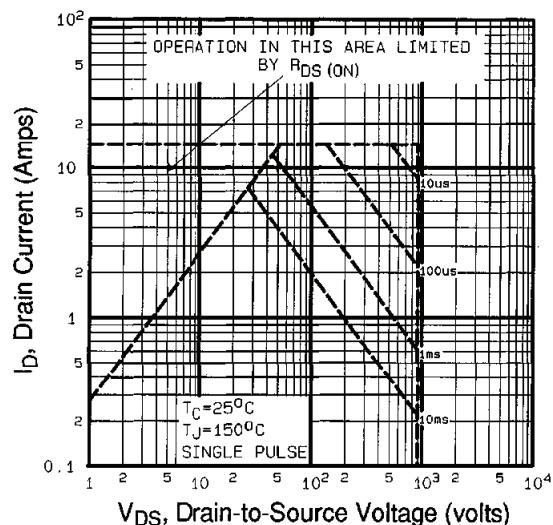


Fig. 8 - Maximum Safe Operating Area

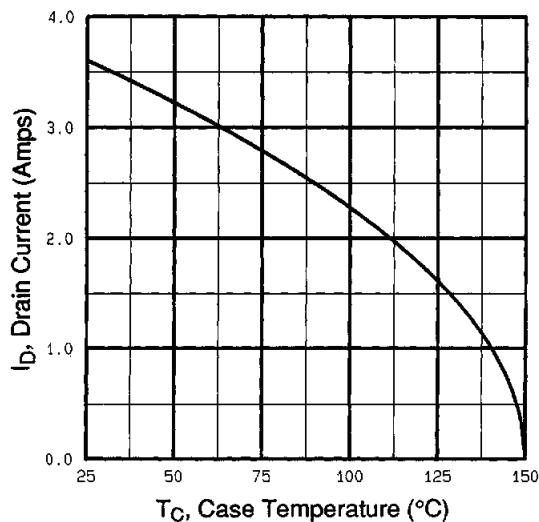


Fig. 9 - Maximum Drain Current vs. Case Temperature

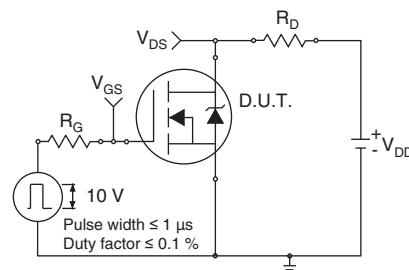


Fig. 10a - Switching Time Test Circuit

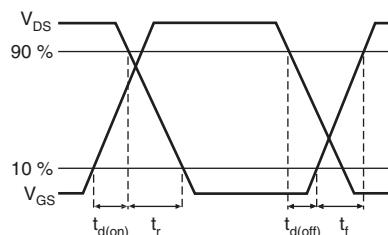


Fig. 10b - Switching Time Waveforms

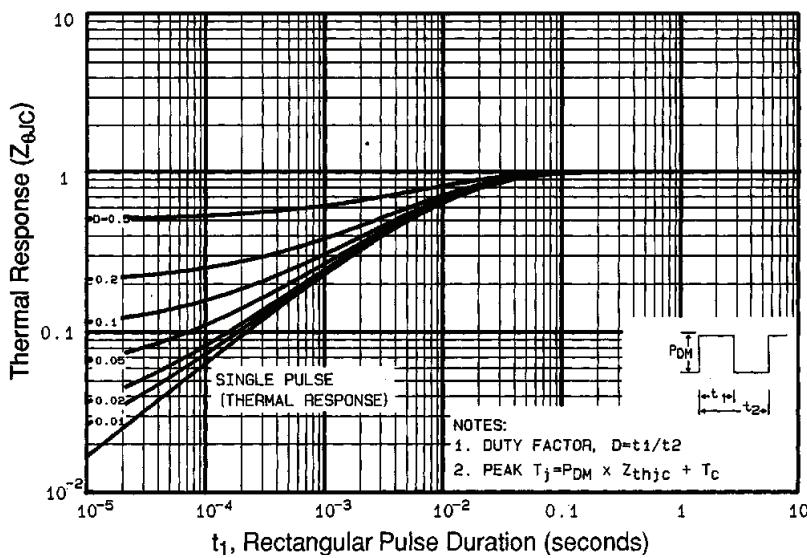


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

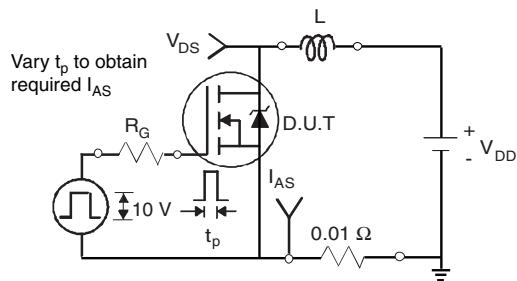


Fig. 12a - Unclamped Inductive Test Circuit

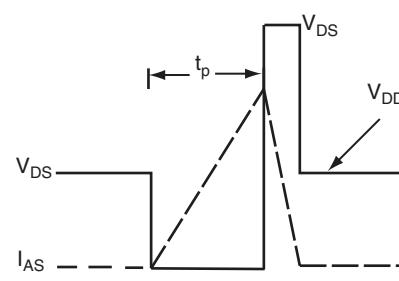


Fig. 12b - Unclamped Inductive Waveforms

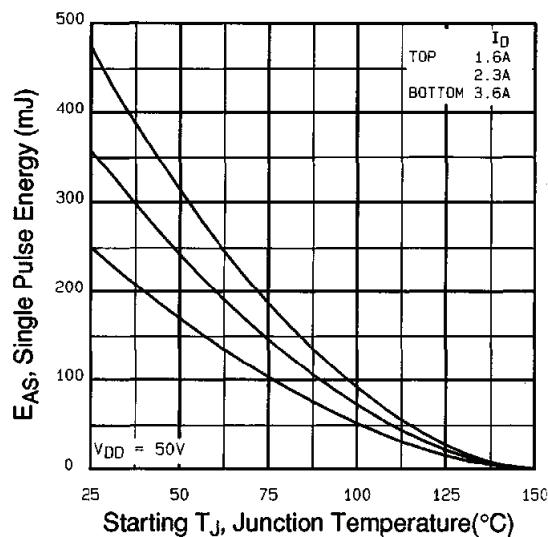


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

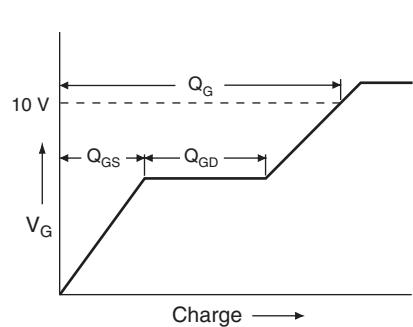


Fig. 13a - Basic Gate Charge Waveform

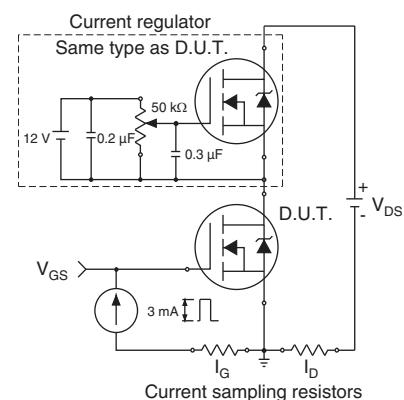


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

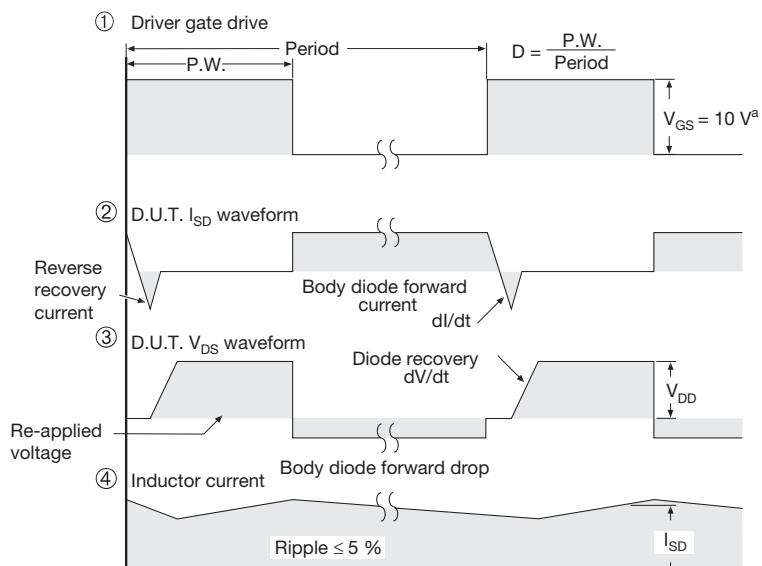
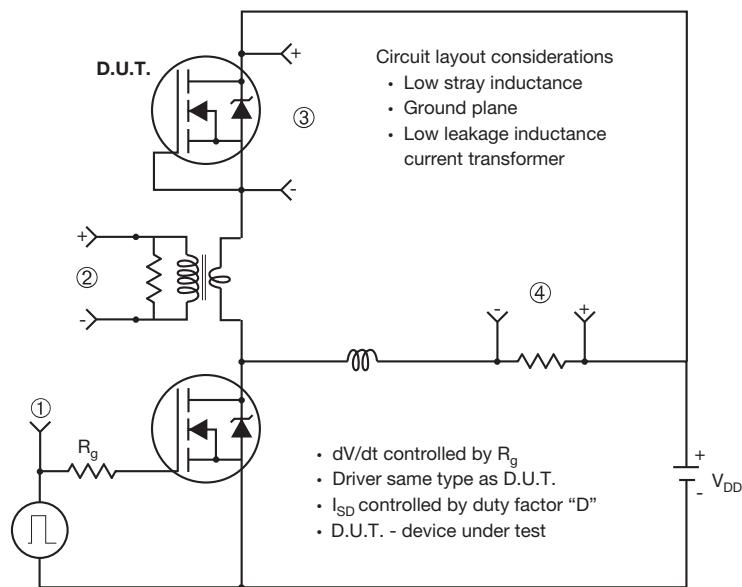
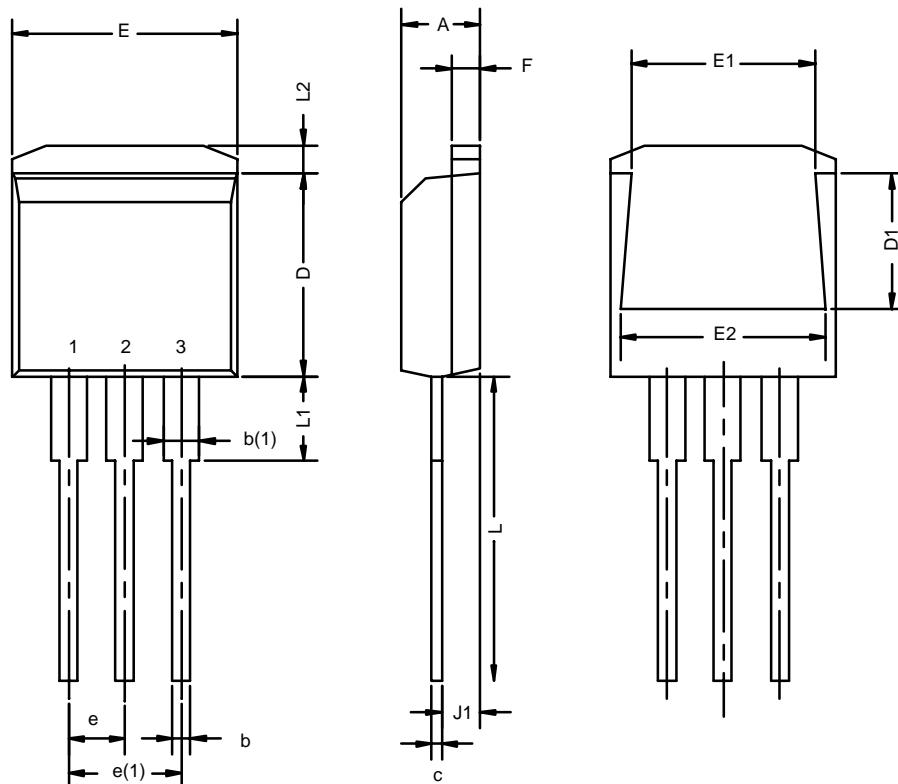


Fig. 14 - For N-Channel

TO-262: 3-LEAD

Dim	MILLIMETERS*		INCHES	
	Min	Max	Min	Max
A	4.32	4.70	0.170	0.185
b	0.64	1.00	0.025	0.039
b(1)	1.14	1.40	0.045	0.055
c	0.36	0.50	0.014	0.020
D	8.64	9.65	0.340	0.380
D1	5.59	6.10	0.220	0.240
e	2.41	2.67	0.095	0.105
e(1)	4.95	5.33	0.195	0.210
E	10.03	10.41	0.395	0.410
E1	7.87	8.64	0.310	0.340
E2	9.02	9.53	0.355	0.375
F	1.14	1.40	0.045	0.055
J1	2.41	2.79	0.095	0.110
L	13.08	14.22	0.515	0.560
L1	-	3.81	-	0.150
L2	1.02	1.40	0.040	0.055

ECN: T-02234—Rev. C, 14-Oct-02
DWG: 5855

*Use millimeters as the primary measurement

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